## **Power MOSFET**

# 30 V, 78 A, Single N-Channel, SO-8 FL

### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

### **Applications**

- CPU Power Delivery
- DC-DC Converters

### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Parameter		Symbol	Value	Unit	
Drain-to-Source Voltage			$V_{DSS}$	30	V
Gate-to-Source Voltage			$V_{GS}$	±20	V
Continuous Drain Current R <sub>θJA</sub>		$T_A = 25^{\circ}C$ $T_A = 80^{\circ}C$	I <sub>D</sub>	21.7 16.3	Α
(Note 1)  Power Dissipation R <sub>θJA</sub> (Note 1)	Steady	T <sub>A</sub> = 25°C	P <sub>D</sub>	2.57	W
Continuous Drain Current R <sub>θJA</sub> ≤ 10 s (Note 1)		$T_A = 25^{\circ}C$ $T_A = 80^{\circ}C$	I <sub>D</sub>	34.8 26.0	Α
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$		T <sub>A</sub> = 25°C	P <sub>D</sub>	6.6	W
Continuous Drain Current R <sub>0JA</sub>	State	T <sub>A</sub> = 25°C	I <sub>D</sub>	11.9	Α
(Note 2)		T <sub>A</sub> = 80°C		8.9	
Power Dissipation $R_{\theta JA}$ (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.77	W
Continuous Drain Current Raic		T <sub>C</sub> = 25°C	I <sub>D</sub>	78	Α
(Note 1)		T <sub>C</sub> =80°C		58	
Power Dissipation R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	33	W
Pulsed Drain Current	$T_A = 25^{\circ}$	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	174	Α
Current Limited by Pa	Current Limited by Package T <sub>A</sub> = 25°C			80	Α
Operating Junction ar Temperature	Operating Junction and Storage Temperature		T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C
Source Current (Body	Source Current (Body Diode)		I <sub>S</sub>	30	Α
Drain to Source dV/dt		dV/d <sub>t</sub>	7.0	V/ns	
Single Pulse Drain-to-Source Avalanche Energy ( $T_J = 25^{\circ}C$ , $V_{GS} = 10$ V, $I_L = 41$ A <sub>pk</sub> , $L = 0.1$ mH, $R_{GS} = 25 \Omega$ ) (Note 3)		E <sub>AS</sub>	84	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

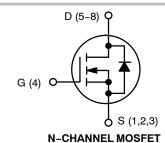
- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.
- 3. This is the absolute maximum ratings. Parts are 100% tested at  $T_J = 25^{\circ}\text{C}$ ,  $V_{GS} = 10 \text{ V}$ ,  $I_I = 29 \text{ A}$ ,  $E_{AS} = 42 \text{ mJ}$ .



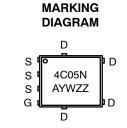
### ON Semiconductor®

### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
30 V	3.4 m $\Omega$ @ 10 V	78 A
30 V	5.0 mΩ @ 4.5 V	76 A







A = Assembly Location Y = Year

W = Work Week
ZZ = Lot Traceabililty

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4C05NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NTMFS4C05NT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	3.8	
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	48.6	°C/W
Junction-to-Ambient - Steady State (Note 5)	$R_{\theta JA}$	161.7	C/VV
Junction-to-Ambient - (t ≤ 10 s) (Note 4)	$R_{ heta JA}$	19	

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
   Surface-mounted on FR4 board using the minimum recommended pad size.

### **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•						
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS}$ = 0 V, $I_{D}$ = 250 $\mu A$		30			V
Drain-to-Source Breakdown Voltage (transient)	V <sub>(BR)DSSt</sub>	V <sub>GS</sub> = 0 V, I <sub>D(aval)</sub> = 12.6 A, T <sub>case</sub> = 25°C, t <sub>transient</sub> = 100 ns		34			٧
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				12		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 25°C			1.0	
			T <sub>J</sub> = 125°C			10	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = ±20 V				±100	nA
ON CHARACTERISTICS (Note 6)	•					•	
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 250 μΑ	1.3		2.2	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.1		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 30 A		2.7	3.4	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		4.0	5.0	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 15 A			68		S
Gate Resistance	$R_{G}$	T <sub>A</sub> = 25°C			1.0		Ω
CHARGES AND CAPACITANCES	•					•	
Input Capacitance	C <sub>ISS</sub>				1972		
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 15 V			1215		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				59		1
Capacitance Ratio	C <sub>RSS</sub> /C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 15 V, f = 1 MHz			0.030		
Total Gate Charge	Q <sub>G(TOT)</sub>				14		
Threshold Gate Charge	Q <sub>G(TH)</sub>				3.3		1
Gate-to-Source Charge	Q <sub>GS</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			6.0		nC
Gate-to-Drain Charge	$Q_{GD}$				5.0		
Gate Plateau Voltage	V <sub>GP</sub>				3.1		V
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			30		nC
SWITCHING CHARACTERISTICS (Note 7)							
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			11		
Rise Time	t <sub>r</sub>				32		1
Turn-Off Delay Time	t <sub>d(OFF)</sub>				21		ns
Fall Time	t <sub>f</sub>				7.0		1

- 6. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.
  7. Switching characteristics are independent of operating junction temperatures.

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Cumbal	Toot Cond	ition	Min	Tvm	Mov	Unit
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 7)						
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			8.0		- ns
Rise Time	t <sub>r</sub>				26		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				26		
Fall Time	t <sub>f</sub>				5.0		
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage V <sub>SD</sub>	$V_{SD}$	VGS = 0 V,	T <sub>J</sub> = 25°C		0.77	1.1	
			T <sub>J</sub> = 125°C		0.62		<del> </del>
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, dI}_{S}/dt = 100 \text{ A}/\mu\text{s,}$ $I_{S} = 30 \text{ A}$			40.2		ns
Charge Time	t <sub>a</sub>				20.3		
Discharge Time	t <sub>b</sub>				19.9		
Reverse Recovery Charge	Q <sub>RR</sub>				30.2		nC

<sup>6.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.
7. Switching characteristics are independent of operating junction temperatures.

### **TYPICAL CHARACTERISTICS**

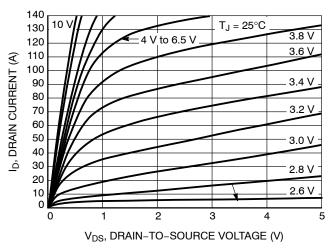


Figure 1. On-Region Characteristics

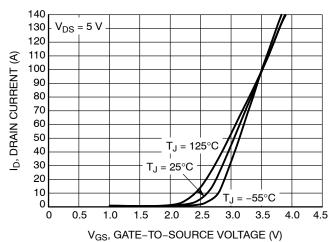


Figure 2. Transfer Characteristics

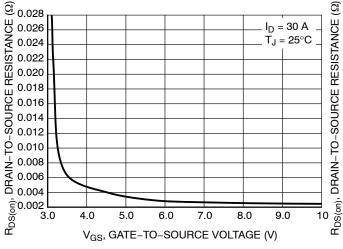


Figure 3. On–Resistance vs.  $V_{\text{GS}}$ 

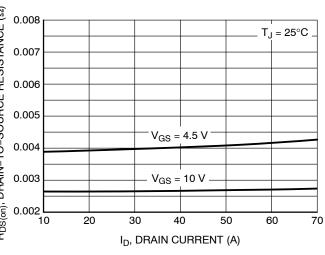


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

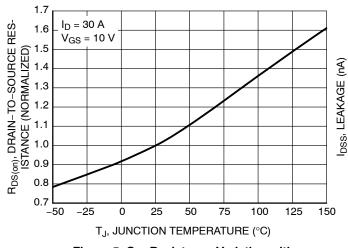


Figure 5. On–Resistance Variation with Temperature

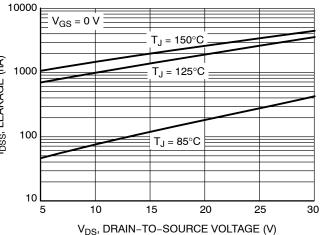


Figure 6. Drain-to-Source Leakage Current vs. Voltage

### **TYPICAL CHARACTERISTICS**

V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (V)

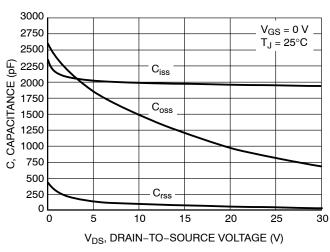


Figure 7. Capacitance Variation

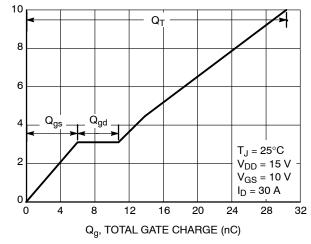


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

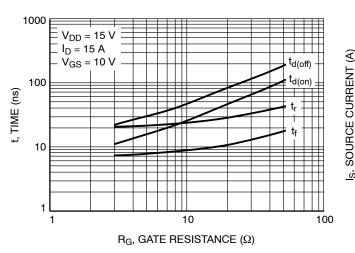


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

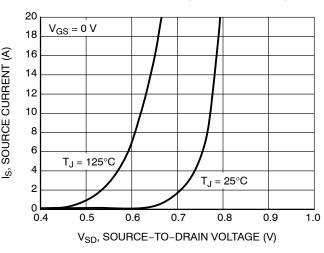


Figure 10. Diode Forward Voltage vs. Current

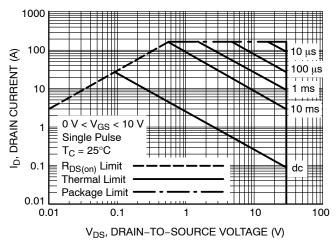


Figure 11. Maximum Rated Forward Biased Safe Operating Area

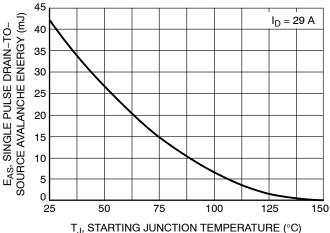


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

### **TYPICAL CHARACTERISTICS**

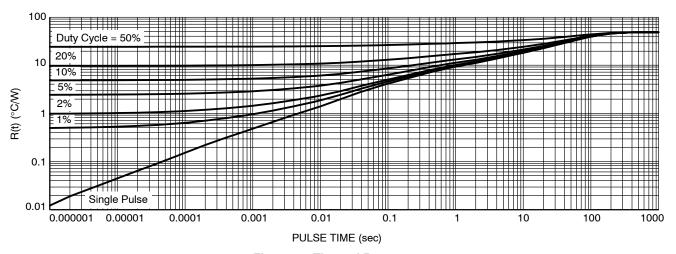


Figure 13. Thermal Response

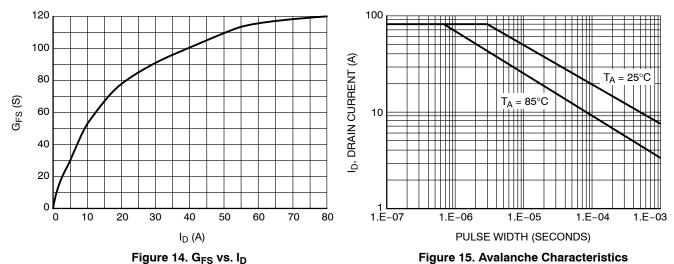
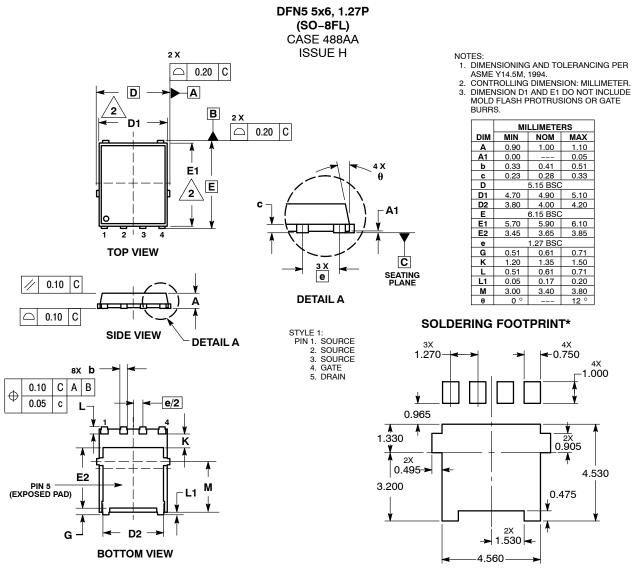


Figure 15. Avalanche Characteristics

### PACKAGE DIMENSIONS



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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